



Can Machine Learning bring a revolution in EMC/SI/PI Design?

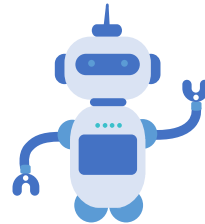
dr. Domenico Spina

INTRODUCTION

- EMC, SI and PI are crucial for modern circuits
 - Complex systems under several physical effects
 - Must be robust to external interferences and be integrated with other components (i.e. digital)
- New production technologies, increased complexity and high operational frequencies bring new challenges to EMC/SI/PI design!

INTRODUCTION

- EMC, SI and PI are crucial for modern circuits
 - Complex systems under several physical effects
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- New production technologies, increased complexity and high operational frequencies bring new challenges to EMC/SI/PI design!
- What is the role of Machine Learning (ML)?



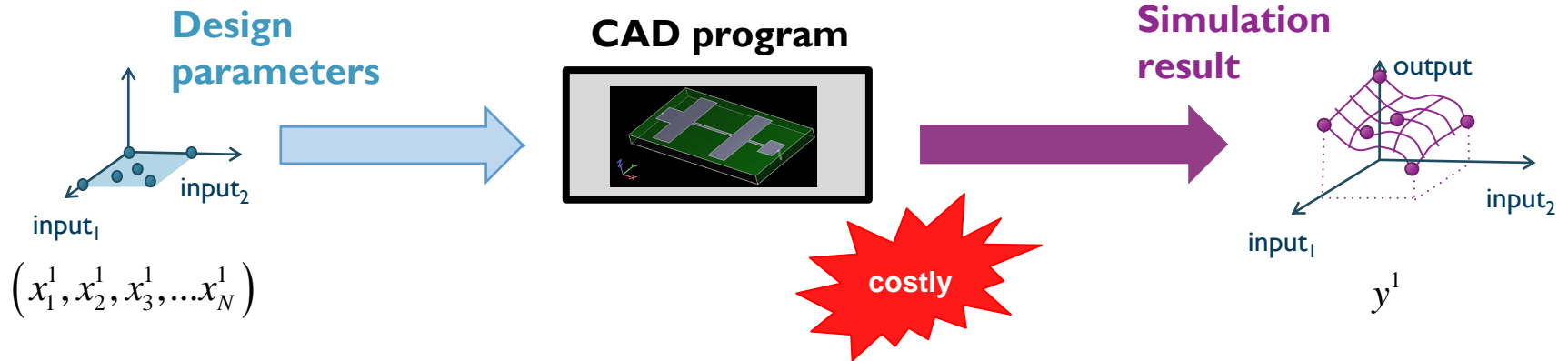
MACHINE LEARNING FOR EMC/SI/PI

- What is ML?
 - ML is a set of methodologies in artificial intelligence (AI)
 - Mathematical techniques able to learn information from a set of data

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Design Problem

1. Design an analog device/circuit in a simulation program (CAD)
2. Define design parameters
3. Tune value of design parameters until desired performance are reached



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- **Dataset**

- Samples of design parameters and corresponding simulation results

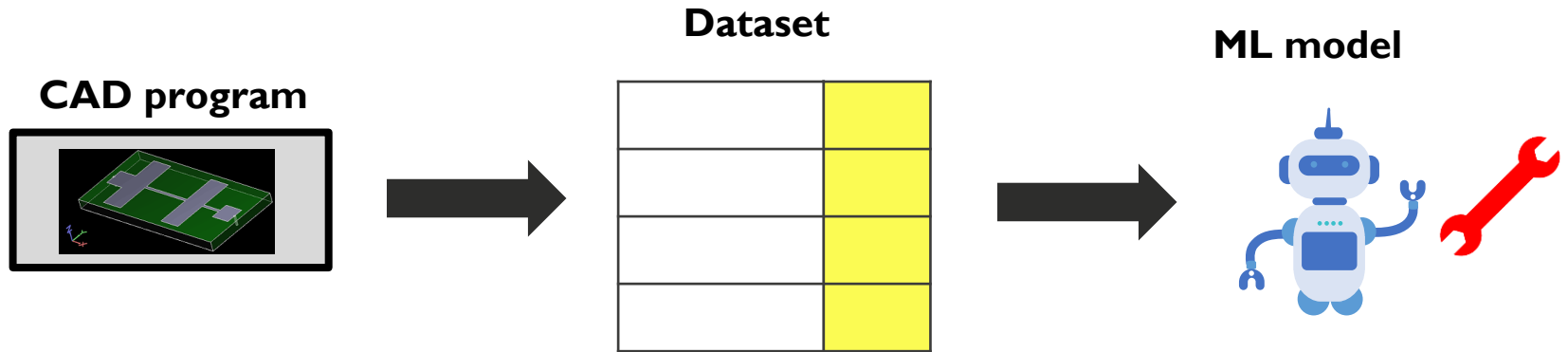
| | |
|---------------------------------------|----------|
| $(x_1^1, x_2^1, x_3^1, \dots, x_N^1)$ | y^1 |
| $(x_1^2, x_2^2, x_3^2, \dots, x_N^2)$ | y^2 |
| \vdots | \vdots |
| $(x_1^M, x_2^M, x_3^M, \dots, x_N^M)$ | y^M |

Ready for ML!

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I. Training

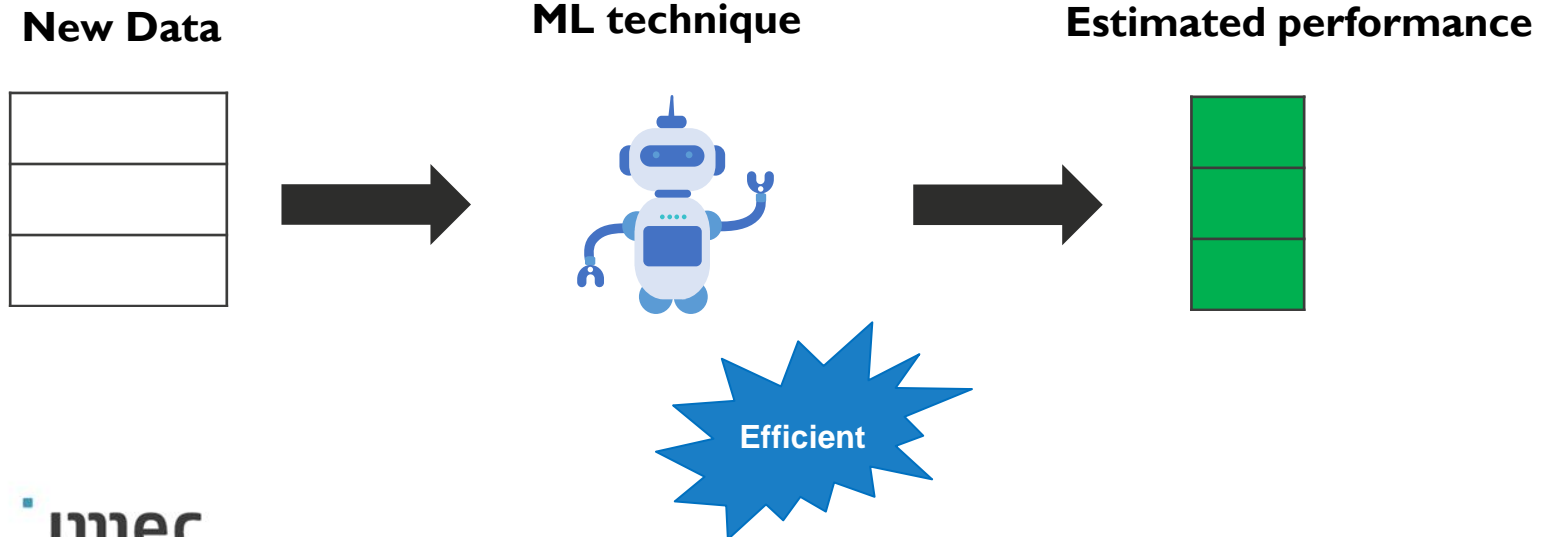
- Goal: **tune model** to learn relation between design parameters and performance metric



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2. Application

- Feed new values of design parameters to ML model
- Model predicts performance of the system



MACHINE LEARNING FOR EMC/SI/PI

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- Able to describe complex systems
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- Accurate estimation (confidence bound)
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- Able to handle large amount of data or design parameters

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- **Examples of ML applications in analog design**
 - Scattering parameters modeling [Jin19, Torun20]
 - Transfer function extrapolation [Bhatti22]
 - Inverse problems [Xiao21, Wu22]
 - Optimization problems [Garbuglia22, Guo22, Touloupas22]
 - Eye Diagram worst case analysis: [Dolatsara21]
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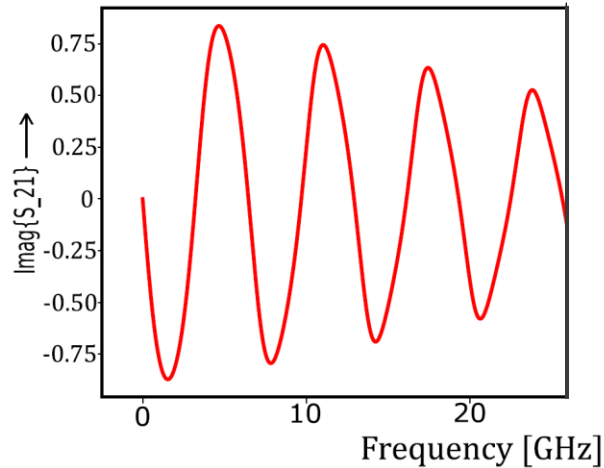
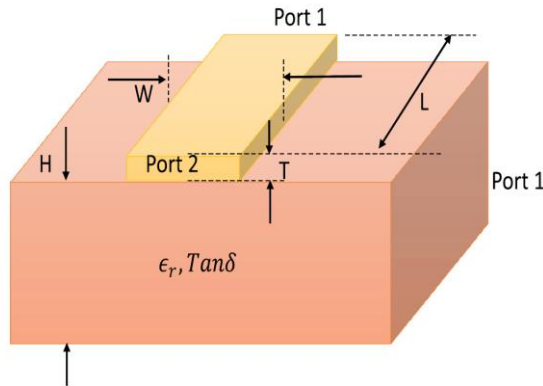
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APPLICATION EXAMPLE

- **Extrapolation S-parameters of a microstrip**
 - Neural Network trained to extrapolate S-parameter data [Bhatti22]

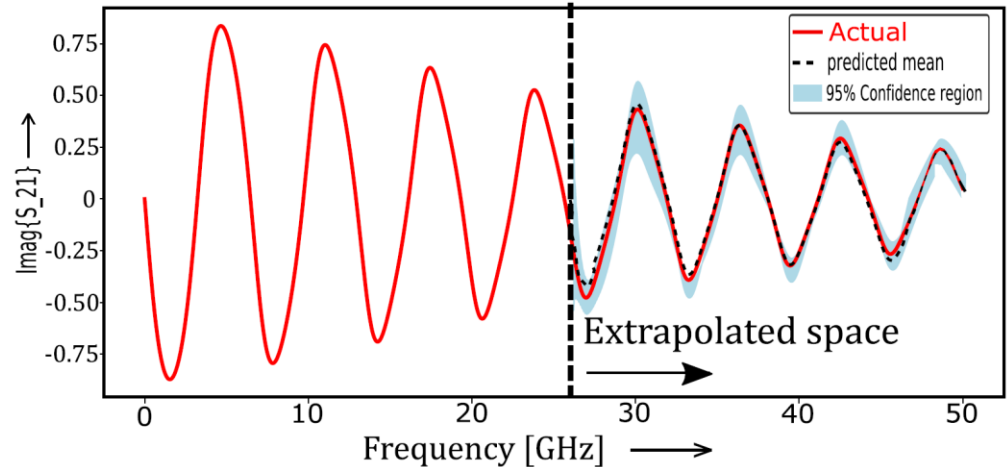
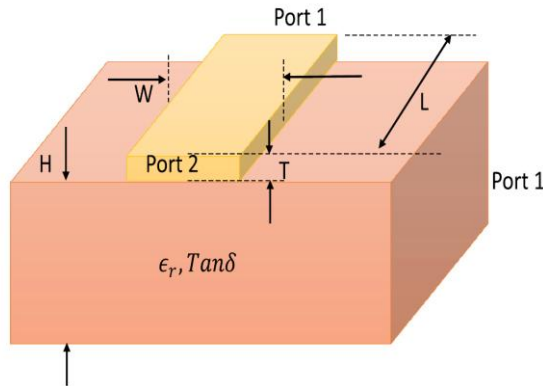


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- **Problem**
 - High cost of generating a dataset for EMC/SI/PI problems
 - Expensive simulations or measurements
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- **Goal**

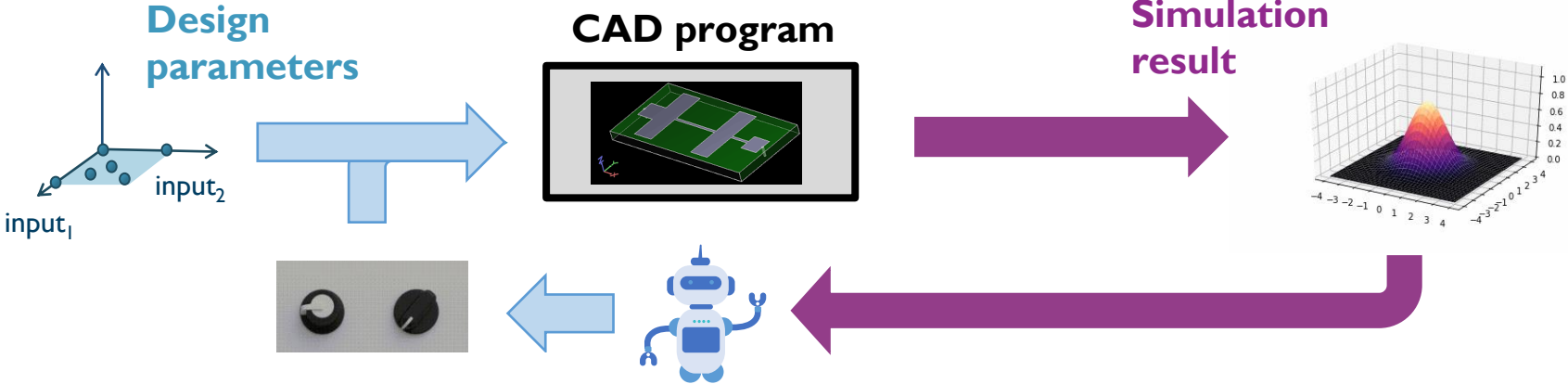
- Minimize number of simulations to build dataset → **Efficiency**
- Maximize the information → **Accuracy**

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- **Goal**
 - Minimize number of simulations to build dataset → **Efficiency**
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- **Solution: Data-efficient ML**
 - **Iteratively** acquire new data in order to maximize information
 - **Adapt** ML model predictions according to new data

DATA-EFFICIENT MACHINE LEARNING

- **Data-efficient ML Framework**



SUMO LAB: RESEARCH TOPICS

- **Our vision**

- Increasing level of automation in analog circuit design
- Enabling accurate and efficient characterization of high-frequency systems
- Increasing efficiency design cycle
- Discovering new design configurations

- **Main Research Area**

- Data-efficient Modeling and Machine Learning
 - Bayesian inference

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CONCLUSIONS

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- **Can ML bring a revolution in EMC/SI/PI design? YES**
- What is needed
 - Include physic-based knowledge in ML
 - Comprehensive approach
 - ML for system- circuit- and device-level
 - Human-in-the-loop
 - Easy to use, interpretable results

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CONCLUSIONS

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**Cooperation between
academia and industry
is fundamental!**

Thanks for your attention!

Questions?

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